



## High-Temperature Sapphire Pressure Sensors For Harsh Environments

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# Project Information

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- Focus: Development of novel machining methods for the fabrication of harsh environment pressure sensors
- Award information
  - ▣ Project title: “High-temperature sapphire pressure sensors for harsh environments”
  - ▣ Award #: DE-FE0012370
  - ▣ Program manager: Sydni Credle
  - ▣ Duration: 3 years (1 year NCE) started Jan 2014
- Project team
  - ▣ UF (Project lead)
  - ▣ FSU

# Technical Objectives

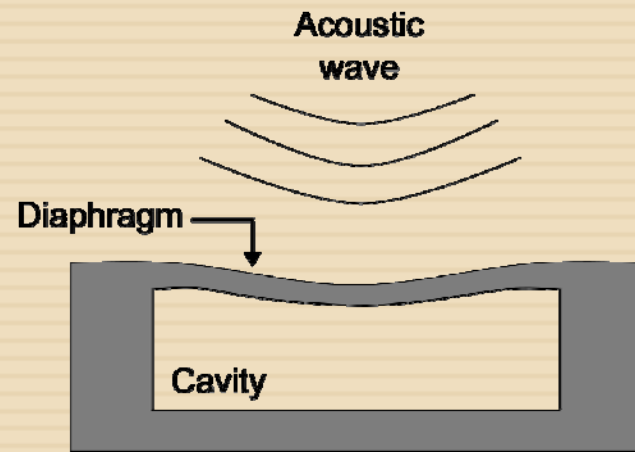
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1. Novel sapphire fabrication processes
  - ▣ Subtractive machining: ultrashort pulse laser (modeling + experimental)
  - ▣ Additive manufacturing: spark plasma sintering
2. Characterize and mitigate thermo-mechanical damage
  - ▣ Statistical modeling of laser pulse-material interactions
3. Fabricate, package, calibrate, and demonstrate sapphire optical pressure sensor
  - ▣ Application for harsh environments ( $> 1000\text{ }^{\circ}\text{C}$  and  $> 1000\text{ psi}$ )

# Outline

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- Introduction
- Thermal Damage Modeling
- Micro and Nano-indentation Mechanics
- Sensor Fabrication
- Acoustic Characterization
- Conclusion/Future work



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Introduction

# Motivation

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- Next generation advanced energy systems will require harsh environment instrumentation:
  - ▣ Process control/closed loop feedback
  - ▣ Increase efficiency, reduce emissions & cost
- Sensor operational requirements
  - ▣ Temperature: >1000 °C and dynamic pressure: up to 1000 psi
  - ▣ Atmosphere: corrosive and/or erosive
- Conventional pressure sensor instrumentation limited to ~500 °C
- Current temperature mitigation techniques:
  - ▣ Stand-off tubes, water cooling

# Transduction Mechanism Selection

	Capacitive	Piezoresistive	Optical
Thermal drift	✓	X	✓
DC measurement	✓	✓	✓
EMI insensitivity	X	X	✓
Harsh environment capability (>500 °C)	X	X	✓
Packaging simplicity	✓	✓	X

- Optical transduction (intensity modulation – optical lever) is selected given our constraints

Pro	Con
Simple/robust fabrication	Lower sensitivity
Incoherent source	
Single or multimode fibers	

# Material Selection

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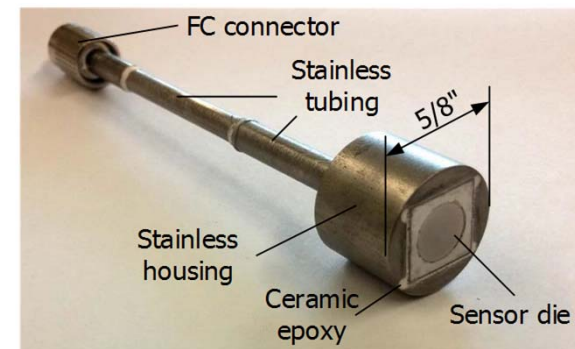
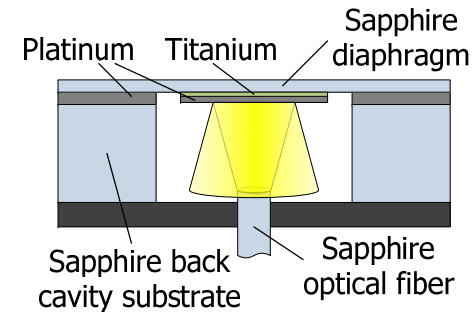
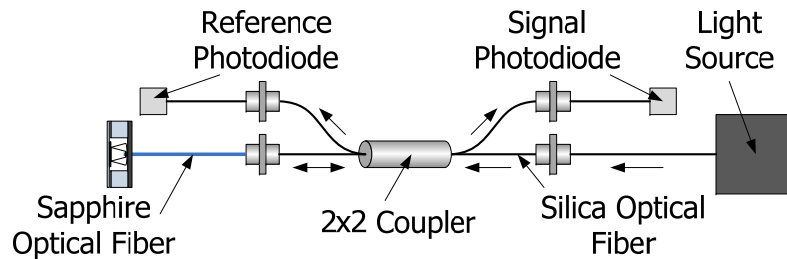
	Silicon Carbide	Diamond	Sapphire
Transparency	✓	✗	✓
Bulk substrate availability	✓	✗	✓
Optical fiber availability	✗	✗	✓
Minimal film stress	✗	✗	✓
Well-established μ-machining processes	✗	✗	✗

- Benefits of sapphire
  - High melting point (2053 °C)
  - Resistance to chemical corrosion
  - Excellent hardness
  - Large transmission window (200 nm – 5 μm)
  - Multimode optical fibers available



# Proof-of-Concept Device (UF)

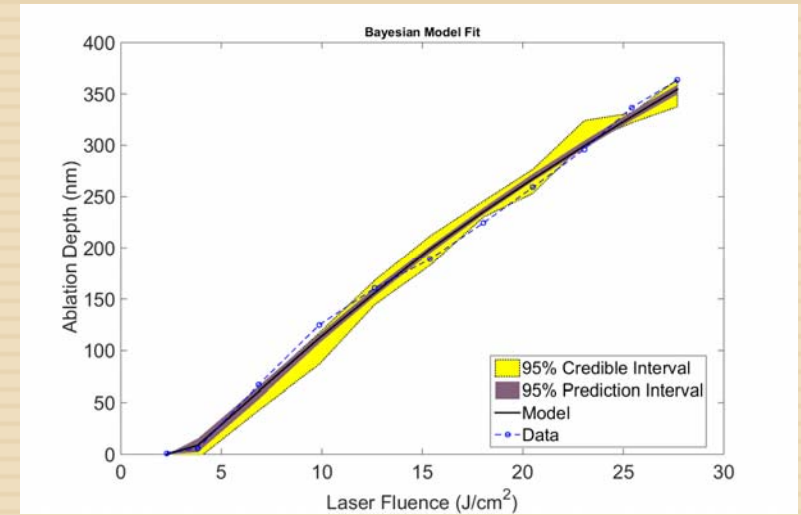
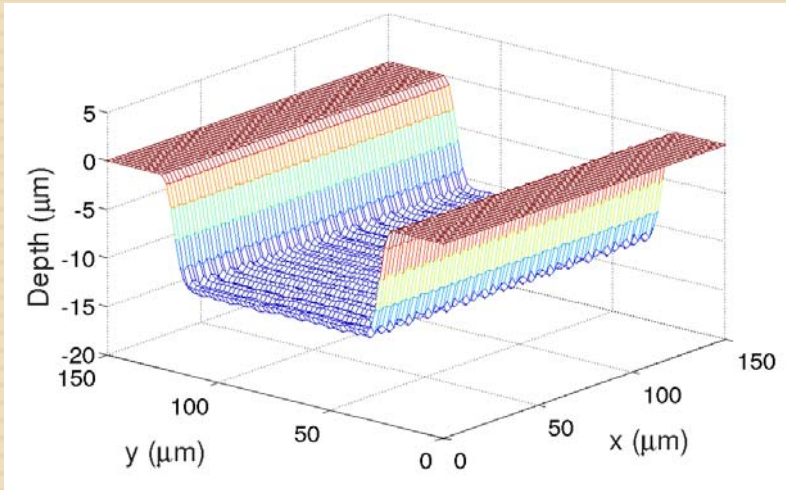
- Diaphragm
  - ▣ 8 mm diameter, 50  $\mu\text{m}$  thick
  - ▣ Platinum reflective surface
- Configuration
  - ▣ Single send/receiver fiber
  - ▣ Sapphire/silica fiber connection
  - ▣ Reference photodiode



# Achievements

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- Quantified structure-properties relations in laser machined sapphire
  - ▣ Enhanced fracture resistance and nominal strength increase
  - ▣ Dislocation formation and amorphous material structure
- Model formulation
  - ▣ Continuum light-matter predictions and uncertainty quantification of sapphire laser ablation
  - ▣ Finite element estimation of single crystal nanoindentation in sapphire
- Laser micromachining
  - ▣ Model prediction matches experimental data
  - ▣ Higher fluence and number of cut passes reduces sidewall angle
  - ▣ Increasing number of passes improves uniformity



# Laser Ablation Modeling

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- Quantified key material physics associated with pulsed picosecond laser ablation of sapphire
- Maxwell equations coupled to time-dependent internal state electronic structure variable
  - ▣ Gaussian laser pulse excitation evaluated over a range of intensities
  - ▣ Electromagnetics coupled to rate dependent electronic material excitation

$$L = L_F + L_I + L_M$$
$$\Pi_D = - \sum \frac{1}{2} \beta^\alpha \dot{y}_i^\alpha \dot{y}_i^\alpha$$

Lagrangian of free space ( $L_F$ ), electromagnetic interaction energy ( $L_I$ ), and material energy ( $L_M$ )  
Entropy generation function,  $\beta^\alpha$  – inverse mobility,  $\dot{y}_i^\alpha$  – rate of change of electronic material structure

- Minimization of Lagrangian and entropy generation leads to balance equations

# Numerical Implementation

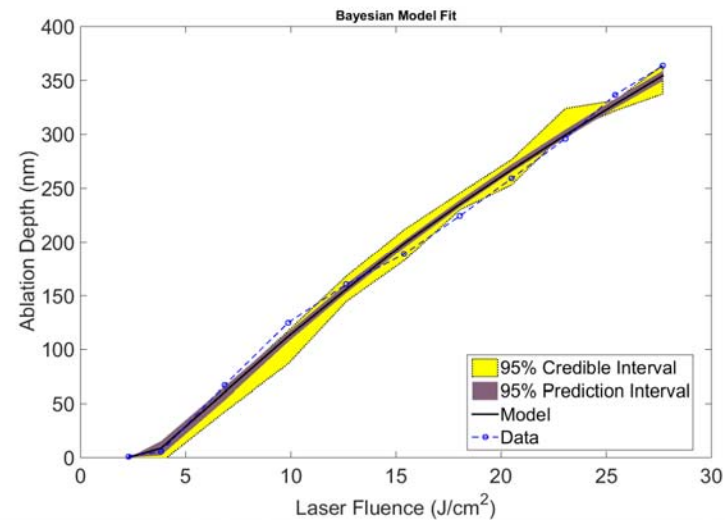
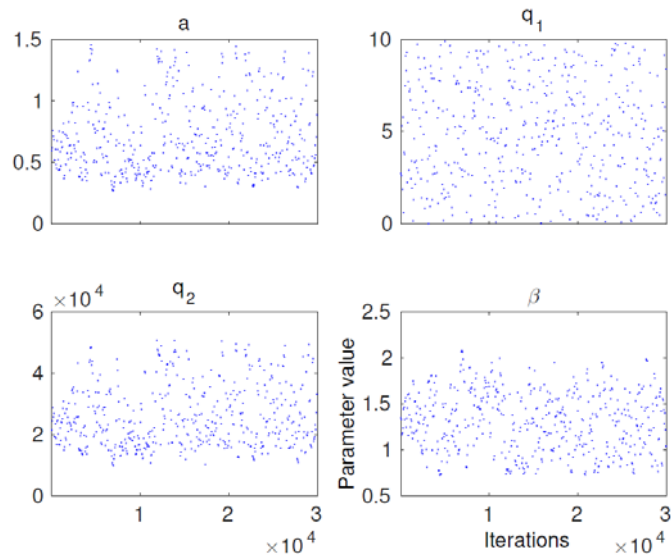
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- Balance equation for electronic structure
  - ▣ Phase field type equation → sharp interface limit
  - ▣ Tracks irreversible laser ablation on sapphire material surface
- Finite difference formulation
  - ▣ Error convergence of spatial and time discretization conducted
- Interaction energy within Lagrangian
  - ▣ Two light-matter constitutive models formulated
  - ▣ Robust model estimates of excited state model parameters
    - Quantified correlations between electron density of sapphire and complex permittivity governing light absorption

# Uncertainty Quantification (UQ)

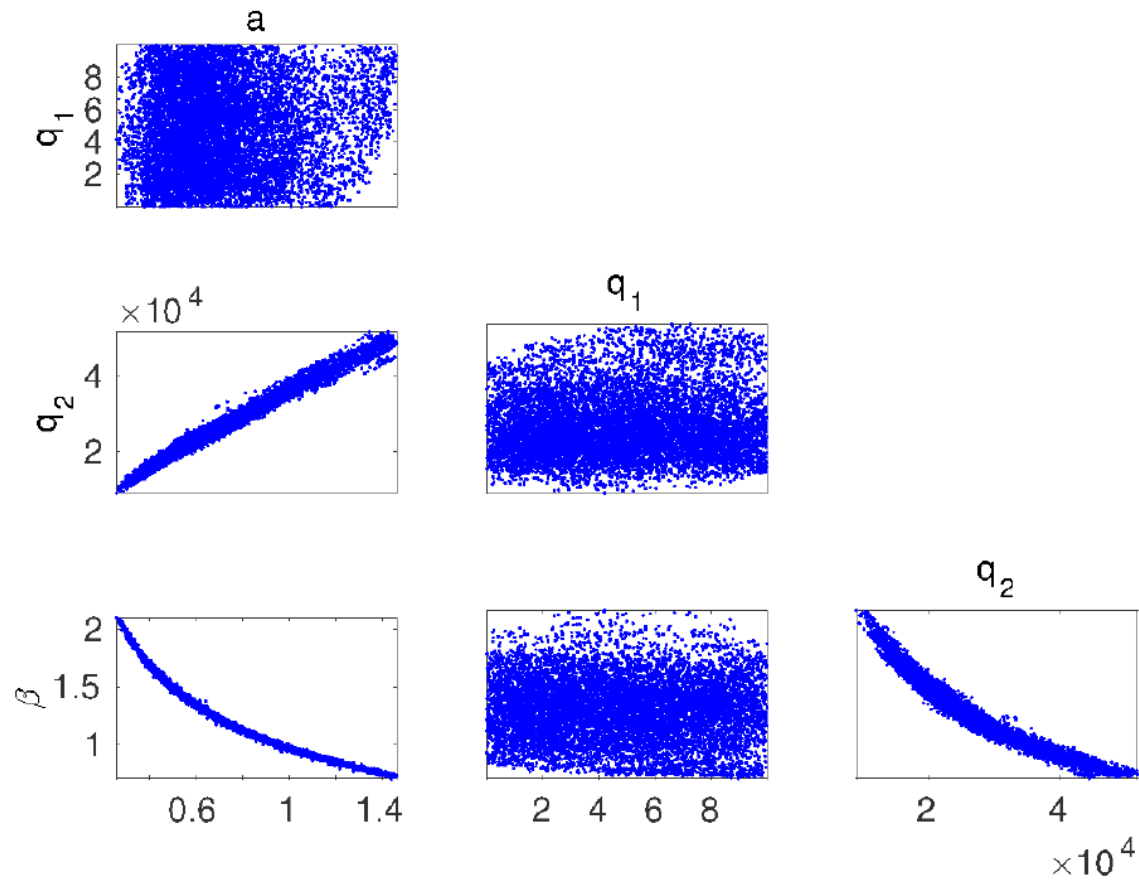
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- Bayesian UQ used to validate the model in light of data
  - ▣ Markov Chain Monte Carlo (MCMC) numerically implemented using delayed rejection adaptive Metropolis (DRAM)
- 1D model approximation due to computational limits
  - ▣ Model sampled  $3 \times 10^4$  times to achieve converged posterior densities



# Parameter Correlation

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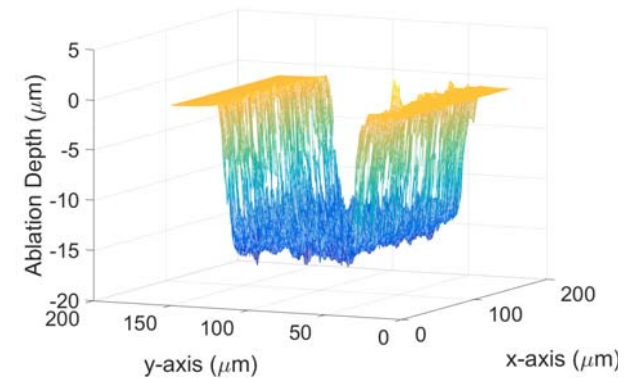


# Three Dimensional Extrapolation

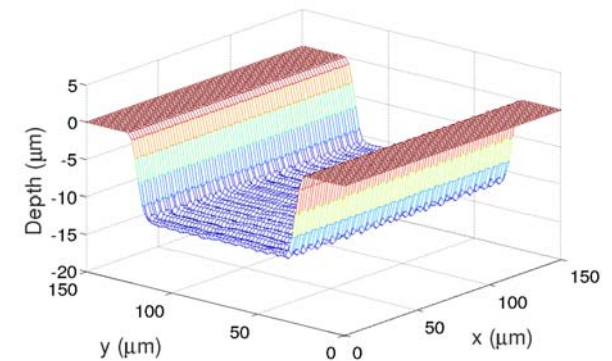
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- One dimensional model calibration extrapolated to 3D
  - ▣ Reasonable correlation with data
  - ▣ Electronic relaxation:  $\tau \sim 4$  fs
- Sensitivity and error analysis
  - ▣ Parameter sensitivity critical for 3D predictions
  - ▣ Average experimental depth of ablation:  $13.8 \mu\text{m}$
  - ▣ Average simulated depth of ablation:  $11.3 \mu\text{m}$

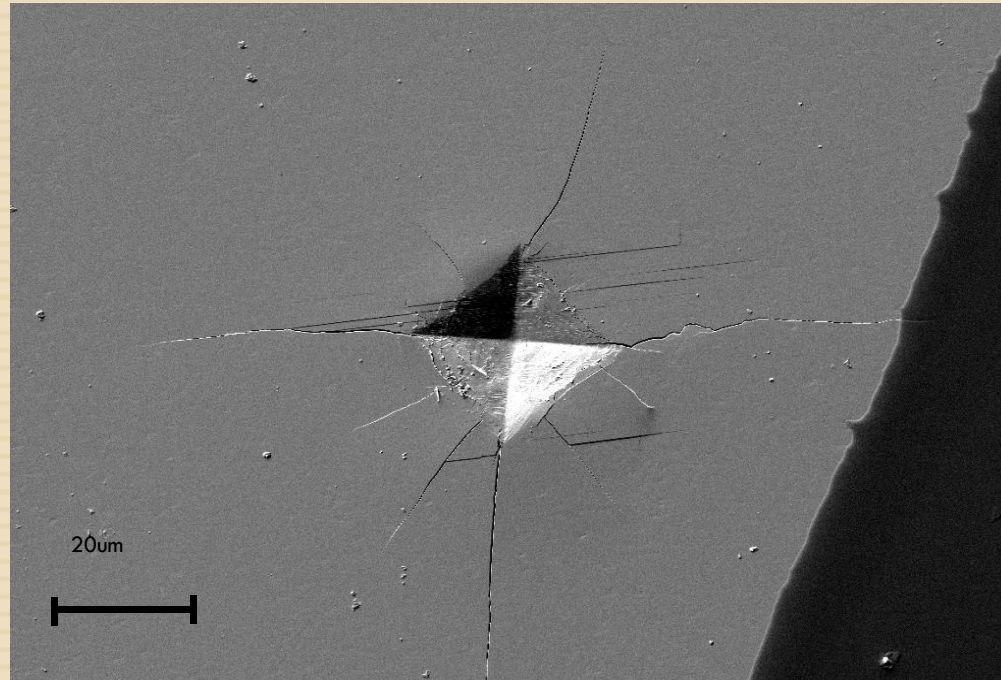
Experimental Ablation Surface



Simulation of Ablation







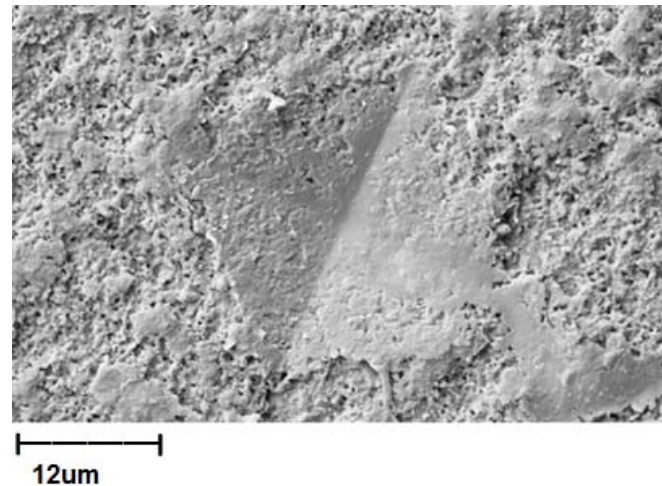
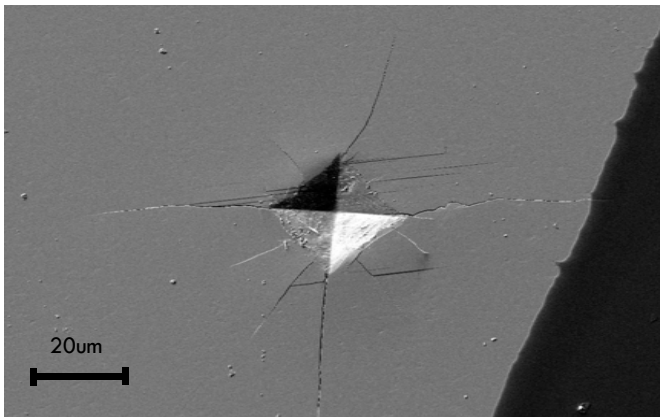
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## Micro and Nanoindentation Mechanics

# Laser Ablated Fracture Resistance

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- Enhanced toughness in laser machined sapphire
  - ▣ No observable cracks from microindentation
- Prior nanoindentations (UF group) illustrate differences in force-displacement curves
- Dislocations induced by laser ablation process
  - ▣ Confirmed from transmission electron microscopy (FSU group)



# Model Development

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- Solid mechanics of sapphire coupled to single crystal dislocation slip system model
- Kinematics broken into elastic ( $\mathbf{H}^e$ ) and plastic ( $\mathbf{H}^p$ ) components

$$\nabla \mathbf{u} = \mathbf{H}^e + \mathbf{H}^p$$

- Plastic strain dependent upon a set of single crystal slip systems ( $\alpha$ )

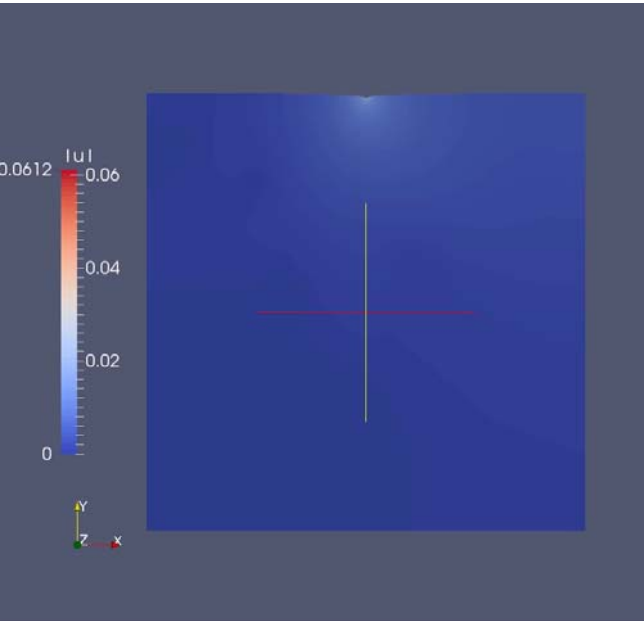
$$\mathbf{H}^p = \sum_{\alpha} \gamma^{\alpha} \mathbf{m}^{\alpha} \mathbf{s}^{\alpha}$$

- Time evolution equation for slip magnitude

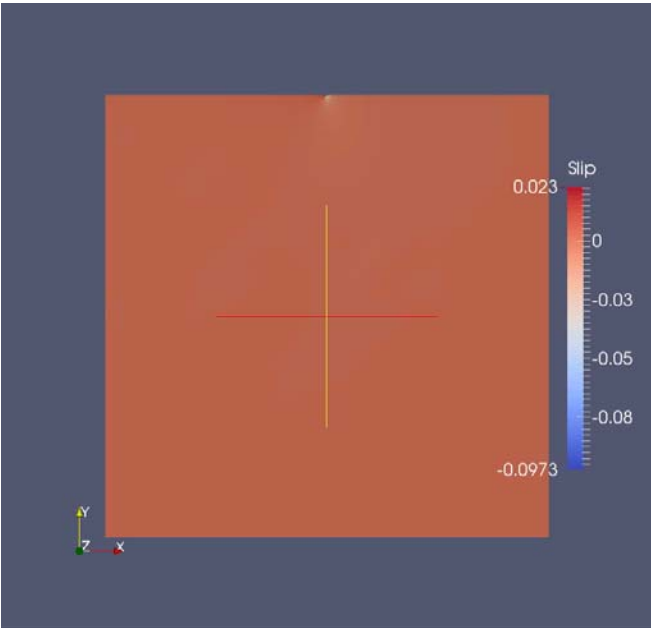
$$\dot{\gamma}^{\alpha} = A \mathbf{m}^{\alpha} \cdot \boldsymbol{\sigma} \cdot \mathbf{s}^{\alpha}$$

- Finite element model implemented in FEniCS
  - ▣ Penalty method introduced to accommodate nanoindentation contact mechanics

# Results



Displacement Field



Slip magnitude

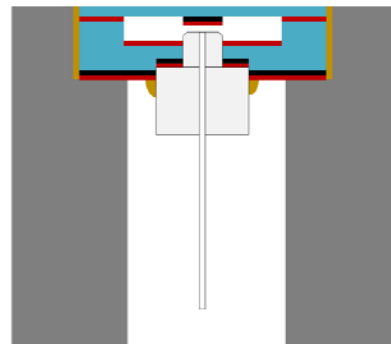
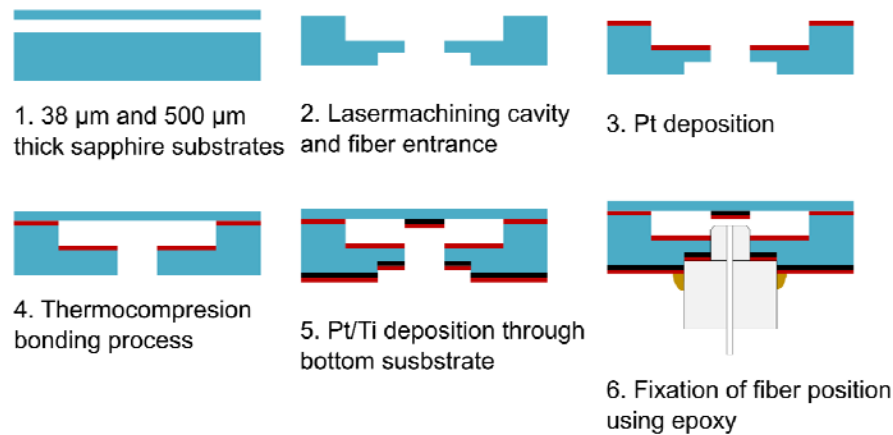


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Sensor Fabrication

# Sensor Fabrication – Process Flow

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7. Packaging of the sensor

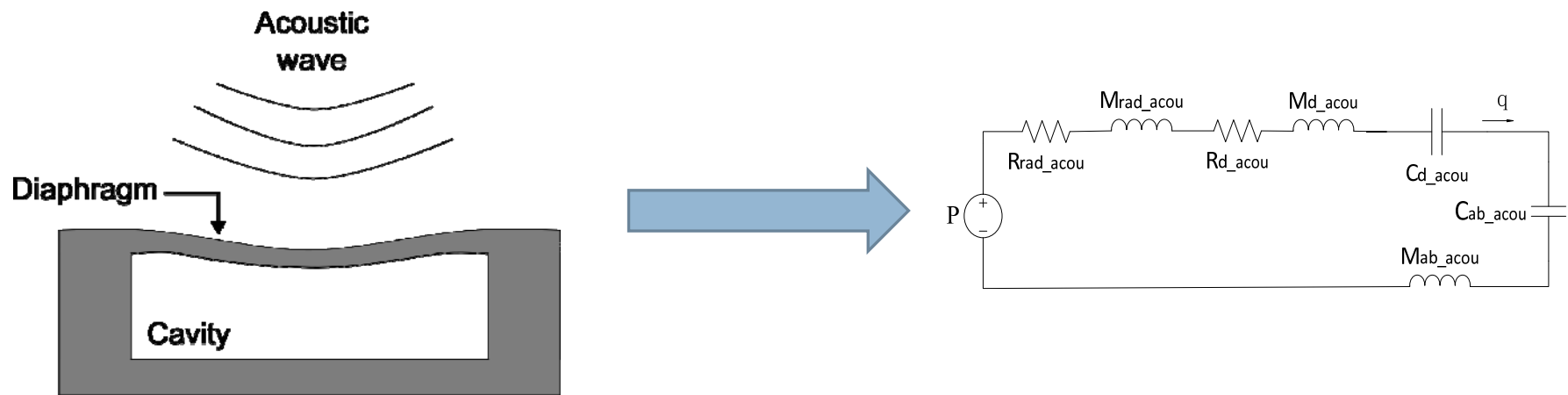
→ Issue 1:  
In-house laser machining tool  
was down for most of the year  
→ Solution 1:  
Externally contracted the  
laser machining of cavity substrate

→ Issue 2:  
Thermocompression bonding tool  
is down  
→ Solution 2:  
Use of ceramic epoxy for bonding  
the two substrates together

# Sensor Fabrication – Mechanical Sensitivity Optimization

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- Aim: optimize diaphragm diameter for best acousto-mechanical sensitivity
- Using lumped element modeling:



# Sensor Fabrication – Mechanical Sensitivity Optimization

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- Aim: optimize diaphragm diameter for best acousto-mechanical sensitivity
- Using lumped element modeling
- Assuming  $200 \text{ kPa}_{\text{max}}$ , and a  $38 \pm 22 \text{ }\mu\text{m}$  thick substrate,  $f_{\text{mincon}}$  solutions:

Thickness ( $\mu\text{m}$ )	Diameter (mm)	Flat-band Sensitivity (nm/Pa)	Maximum deflection ( $\mu\text{m}$ )	Resonant Frequency (kHz)
60	5.4	0.12	24.5	31.3
50	4.4	0.093	18.7	38.1
38	3.4	0.076	15.1	46.0
16	1.4	0.029	5.8	90.7

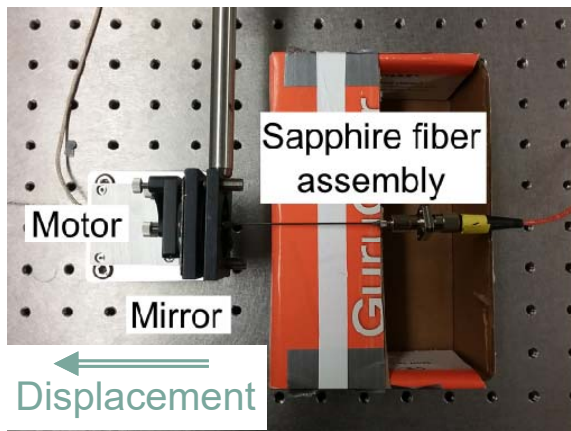
Resulting diameter = 5 mm



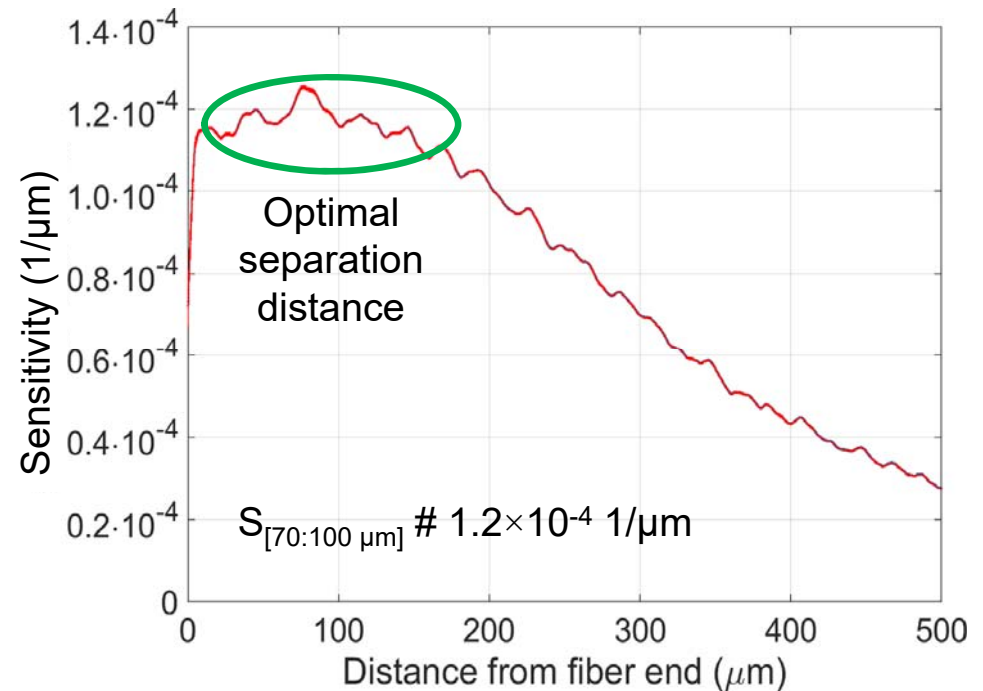
# Sensor Fabrication – Optical Sensitivity Optimization

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- Aim: Find the distance between end of fiber and reflective Pt layer for linear optical response and optimal sensitivity



- FC/PC connector
- 120 μm diam sapphire
- stainless tubing
- epoxy



# Sensor Fabrication – Membrane/Cavity Substrates

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- Laser machining of trenches in both substrates for improved adhesion
- Next step: using alumina ceramic, bond the two wafers together



3. Lasermachining of trenches in both substrates



10 mm

*Cavity Substrate*



*Zoom in (x10)*

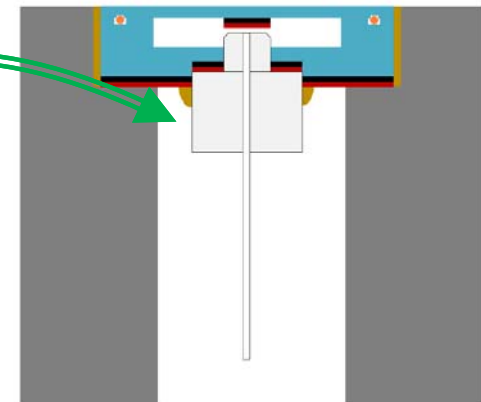


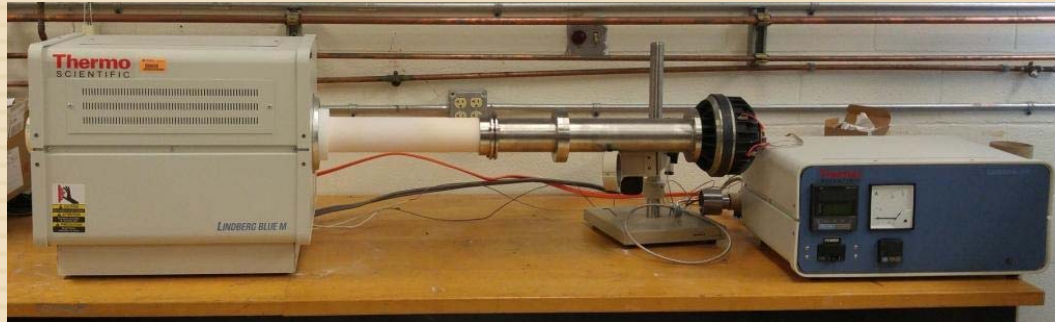
*Membrane Substrate*

# Sensor Fabrication – Optic Fiber Structure

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- Sapphire optic fiber was mounted on:
  - ▣ Stepped ferule
  - ▣ FC connector
  - ▣ Brass tubing for rigidity
    - In the future, to be replaced by alumina





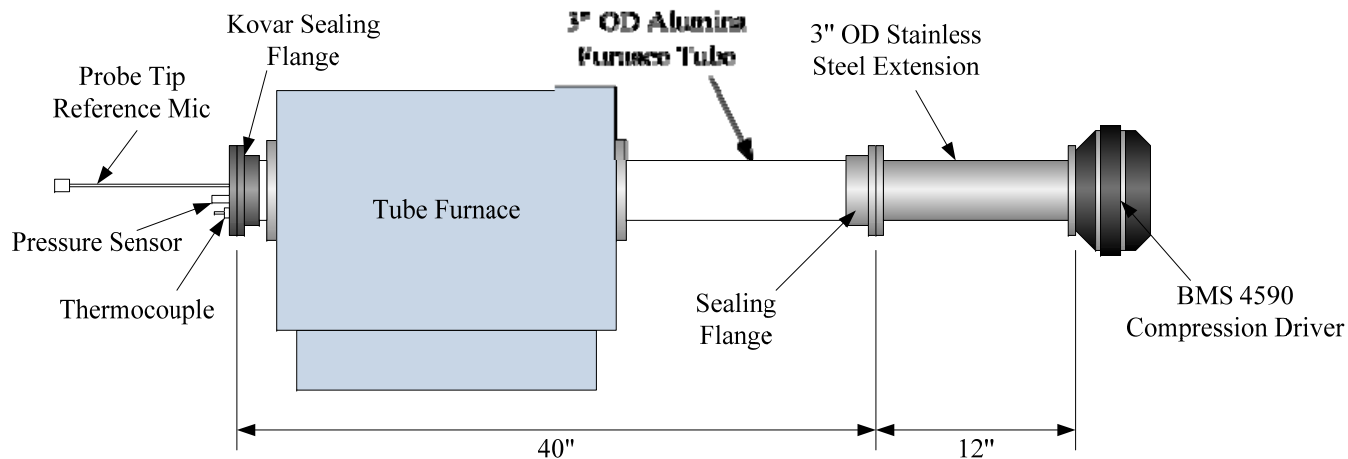
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## Acoustic Characterization

# High Temperature Testing Facility

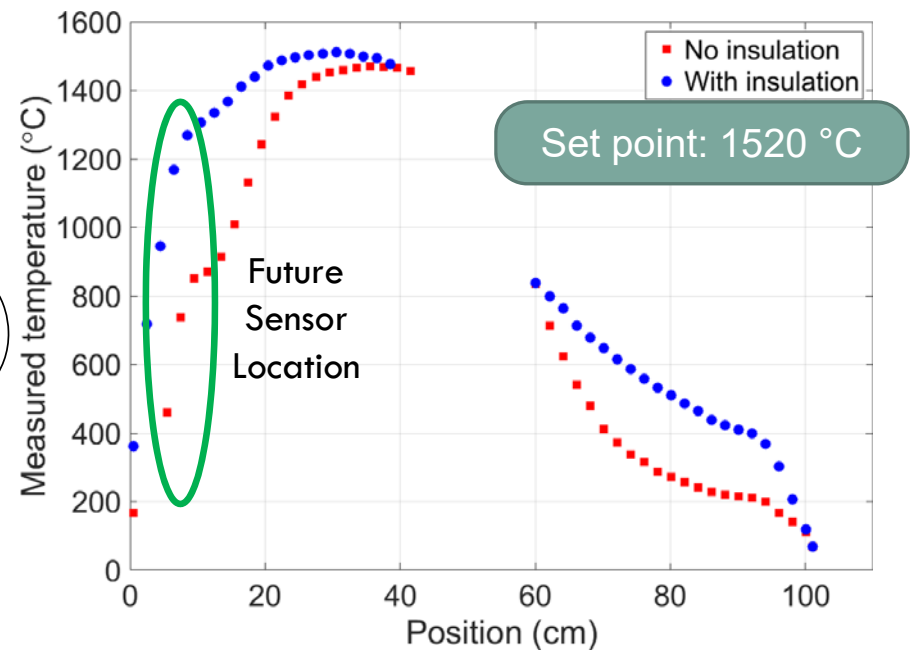
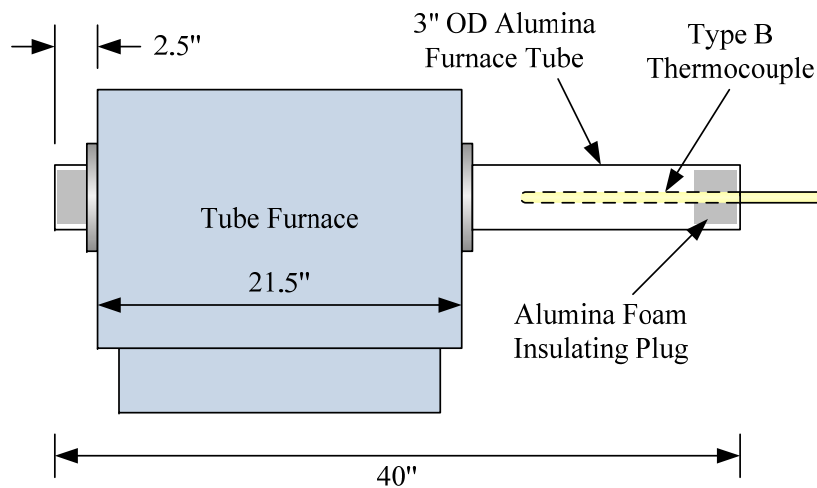
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- Plane Wave Tube (PWT) for acoustic characterization
  - ▣ Speaker generates acoustic pressure waves
  - ▣ Propagate as plane acoustic waves through the tube furnace
  - ▣ Option: tube furnace ON → high temperature capability
  - ▣ Pressure sensor characterized *in situ*



# Step 1: Characterization of Temperature

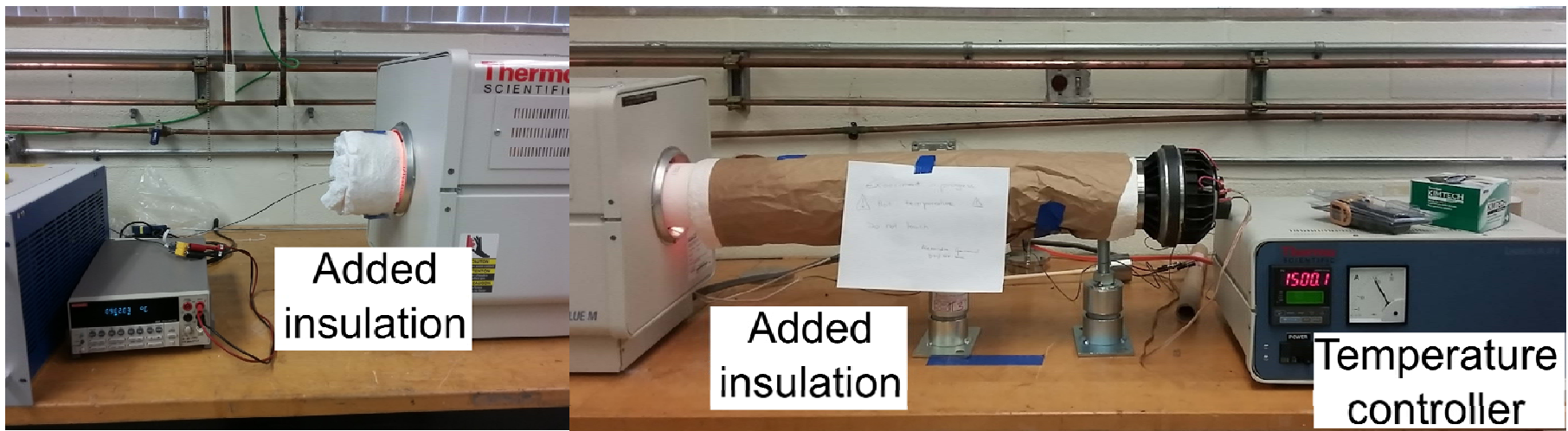
- Aim: acoustic characterization up to 1200 °C
- Measurement of temperature along the PWT
- Added insulation to prevent thermal leak



# Step 1: Characterization of Temperature

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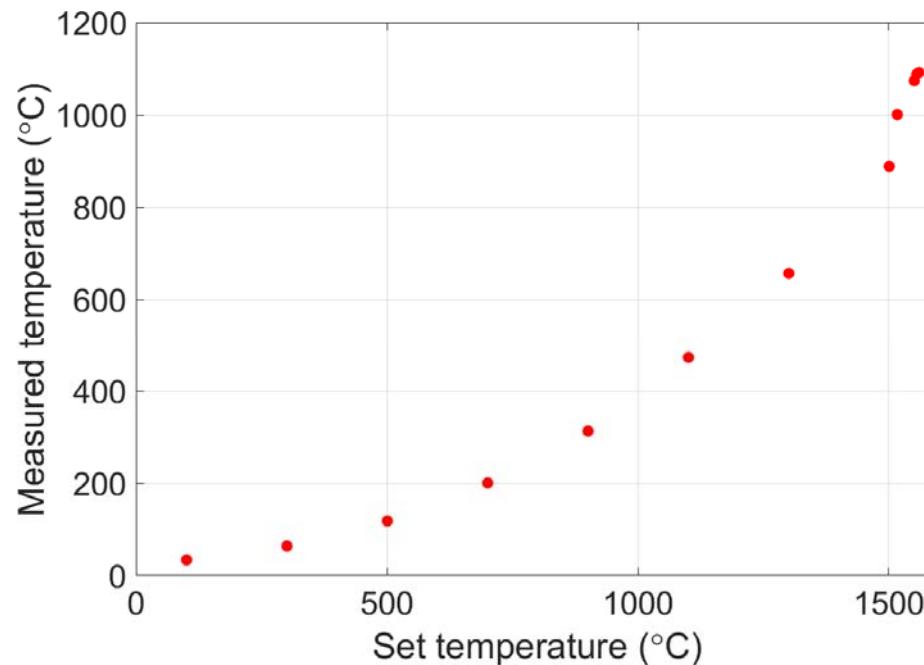
- Aim: acoustic characterization up to 1200 °C
- Measurement of temperature along the PWT
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# Step 1: Characterization of Temperature

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- Aim: acoustic characterization up to 1200 °C
- Measurement of temperature at the future sensor location



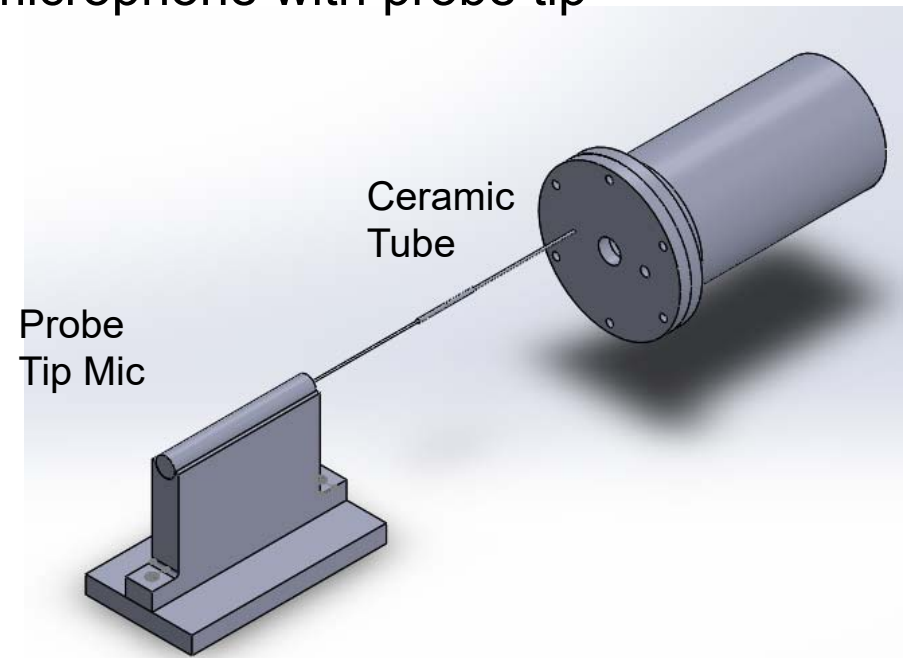
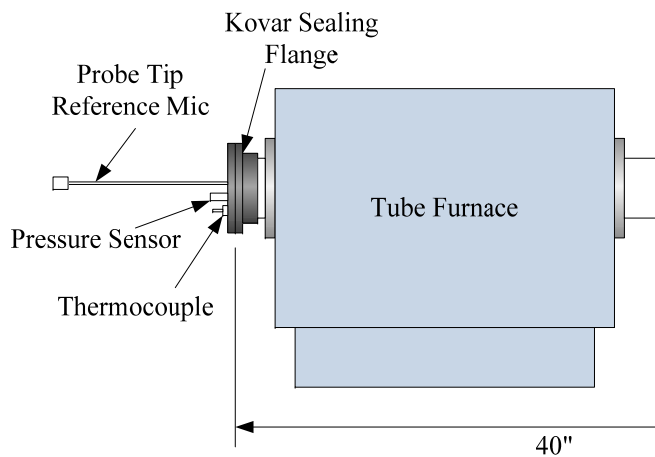
Highest  
measured temperature:  
1092 °C



## Step 2: Acoustic Characterization

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- Aim: Acoustic characterization at high temperatures
- Issue: the acoustic response varies with temperature
- Solution: use of a remote reference microphone with probe tip





# Conclusions

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- Laser Ablation Modeling
  - ▣ Successfully predicted ps laser ablation in 1D and extrapolated 3D to simulate milling
  - ▣ Developed a 2D model of elastic+slip mechanics for nano-indentation in sapphire
- Sensor Fabrication
  - ▣ Determined the separation between fiber and reflective layer for optimal optical sensitivity
  - ▣ Designed cavity and membrane substrates for optimal acousto-mechanical sensitivity
  - ▣ Initiated sensor fabrication
- Acoustic Characterization
  - ▣ Optimized high temperature plane wave tube setup to reach 1100 °C at sensor location
  - ▣ Designed mounting support to hold all the equipment necessary for characterization
    - Thermocouple, remote reference microphone with probe tip, sensor

# Future Work

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- Laser Ablation Modeling
  - ▣ Inferring material property changes in laser machined sapphire via nanoindentation and FEA
  - ▣ Developing UQ tools and planning x-ray measurements to understand laser induced fracture properties
- Sensor Fabrication
  - ▣ Finish fabrication, package and demonstrate proof of concept at room temperature
- Acoustic Characterization
  - ▣ Calibrate PWT acoustic response at high temperatures
  - ▣ Demonstrate sensor capabilities at elevated temperatures



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